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Fairchild Semiconductor FDS2670

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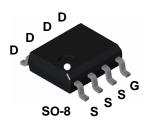
200V N-Channel PowerTrench[®] MOSFET

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

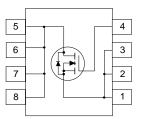
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $\text{RDS}_{(\text{ON})}$ specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.



Features

- 3.0 A, 200 V. $R_{\text{DS(ON)}}$ = 130 m Ω @ V_{GS} = 10 V
- Low gate charge
- Fast switching speed
- High performance trench technology for extremely low R_{DS(ON)}
- High power and current handling capability



Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DSS}	Drain-Source Voltage		200	V	
V _{GSS}	Gate-Source Voltage		±20	V	
I _D	Drain Current – Continuous	(Note 1a)	3.0	A	
	- Pulsed		20		
PD	Power Dissipation for Single Operation	(Note 1a)	2.5	W	
		(Note 1b)	1.2		
		(Note 1c)	1.0		
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	3.2	V/ns	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C	
Therma	I Characteristics				
	Thermal Desistance, Junction to Ambient		FO	0044	

$R_{ heta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1c)	125	°C/W
R _{θJC}	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS2670	FDS2670	13"	12mm	2500 units
	•	•	•	•

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	burce Avalanche Ratings (Note 4	1)	•	•	•	•
W _{DSS}	Single Pulse Drain-Source	$V_{DD} = 100 \text{ V}, I_D = 3.0 \text{ A}$			375	mJ
AR	Avalanche Energy Maximum Drain-Source Avalanche				3.0	А
-/	Current					
Off Char	acteristics					
3V _{DSS}	Drain–Source Breakdown Voltage	$V_{GS}=0~V, \qquad I_D=250~\mu A$	200			V
<u>ΔBVdss</u> ΔTj	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$, Referenced to 25°C		214		mV/°C
DSS	Zero Gate Voltage Drain Current	$V_{DS} = 160 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
GSSF	Gate–Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
GSSR	Gate–Body Leakage, Reverse	$V_{GS} = -20 \text{ V} \qquad V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, \qquad I_D = 250 \ \mu A$	2	4	4.5	V
<u>ΔVGS(th)</u> ΔTJ	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$, Referenced to 25°C		-10		mV/°C
R _{DS(on)}	Static Drain-Source	$V_{GS} = 10 \text{ V}, I_D = 3.0 \text{ A}$		100	130	mΩ
1	On–Resistance On–State Drain Current	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 3.0 \text{ A}, \text{ T}_{J} = 125^{\circ}\text{C}$ $V_{GS} = 10 \text{ V}, \text{ V}_{DS} = 10 \text{ V}$	20	205	275	•
D(on)			20	15		A S
Ĵfs	Forward Transconductance	$V_{DS} = 10 \text{ V}, I_D = 3.0 \text{ A}$		15		3
	Characteristics		1	1000	1	
Ciss	Input Capacitance	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V},$		1228		pF
	Output Capacitance	f = 1.0 MHz		112		pF
C _{rss}	Reverse Transfer Capacitance			17		pF
Switchin	g Characteristics (Note 2)					
d(on)	Turn–On Delay Time	$V_{DD} = 100 V, I_D = 1 A,$		13	23	ns
r	Turn–On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		8	16	ns
d(off)	Turn-Off Delay Time			30	48	ns
f	Turn–Off Fall Time			25	40	ns
ָΩ _g	Total Gate Charge	$V_{DS} = 100 V, I_{D} = 3 A,$		27	43	nC
Q _{gs}	Gate–Source Charge	V _{GS} = 10 V		7		nC
	Gate–Drain Charge			10		nC
Q _{gd}						
	ource Diode Characteristics a	and Maximum Ratings				
	Durce Diode Characteristics a Maximum Continuous Drain–Source				2.1	A

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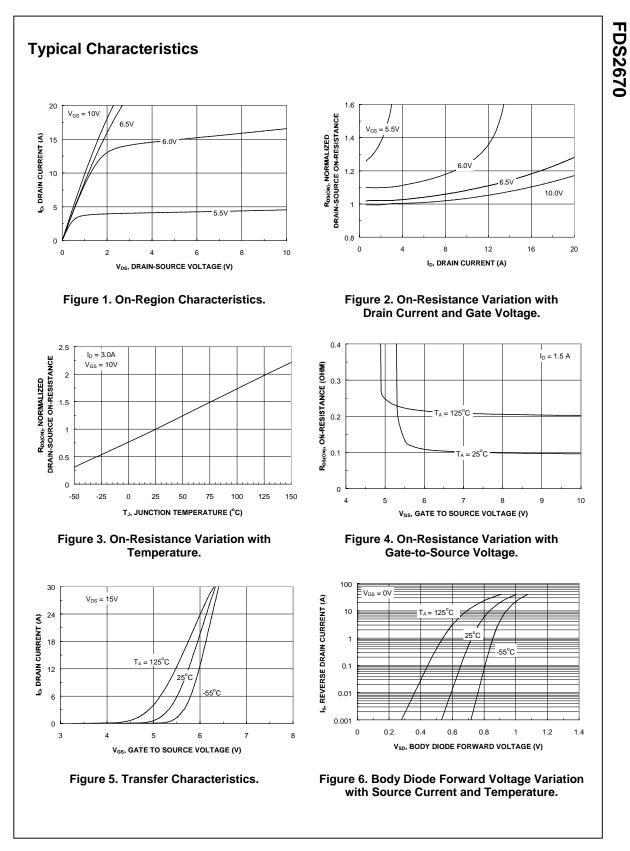
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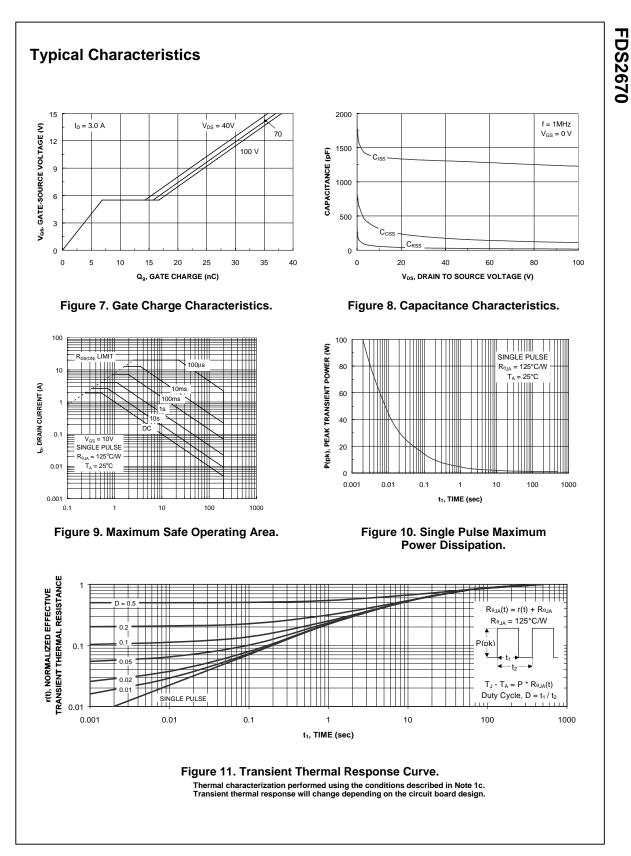
Notes: 1. R _{eJA} is the sum of the the drain pins. R _{eJC} i) junction-to-case and case-to- s guaranteed by design while	ambient thermal resistance where the case the $R_{\theta CA}$ is determined by the user's board design.	rmal reference is defined as the solder mounting surface of
	a) 50°/W when mounted on a 1in ² pad of 2 oz copper	b) 105°/W when mounted on a 0.04 in ² pad of 2 oz copper	c) 125°/W when mounted on a minimum pad.
Scale 1 : 1 on letter size	e paper		
2. Pulse Test: Pulse Wi	dth < 300μs, Duty Cycle < 2.0	%	
3. I _{SD} ≤ 3A, di/dt ≤ 100A	$/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J =$	= 25°C	





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Obsolete

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